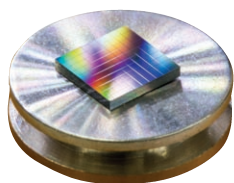
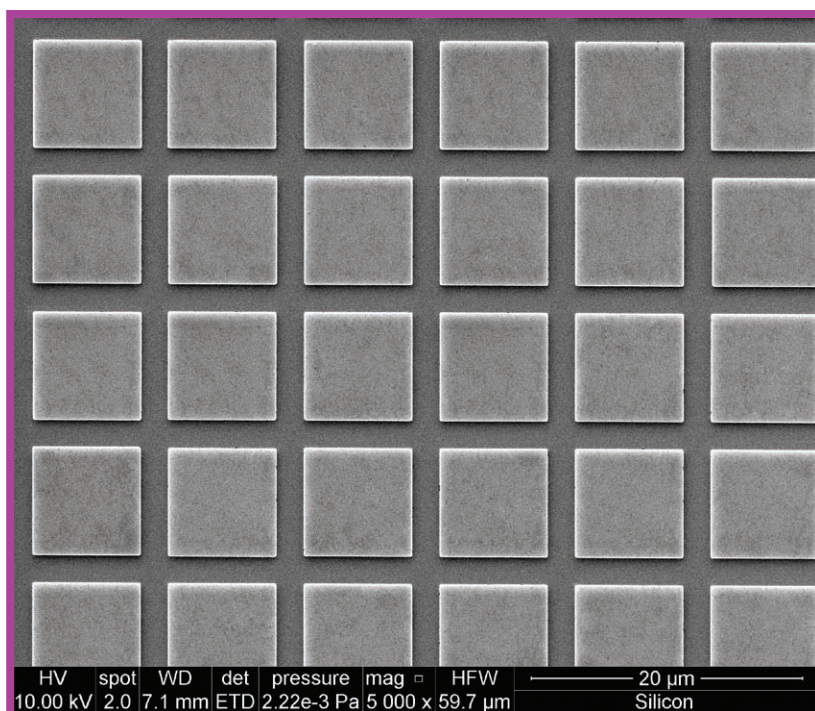


EM RESOLUTIONS
Supporting Electron Microscopy

Silicon test calibration standard - get the best from your SEM

SST silicon test calibration standard is excellent for comparing magnification and assessing distortion in the image field. **SST10** is made of single crystal silicon with overall dimensions 5 x 5mm and 0.5mm thick. Formed by electron beam lithography it is marked with clearly defined squares of periodicity 10µm. The dividing lines are approximately 1.9µm in width and 300nm deep. A broader marking line is written every 500 µm, which serves as a useful calibration for light microscopy and macro-photography. Your sample can also be mounted directly onto a silicon standard for internal calibration and direct measurements.



SST10 - Supplied as standard on a 12.5mm pin stub, it can also be supplied unmounted or on any stub of choice. Each test calibration standard is checked in our laboratory using a light microscope before packing.



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